

S1: (arrow mark) Rs > 99.9% @500-540nm + 1000-1070 nm Rp > 99.8% @507-527nm Rp > 99.9% @1005-1070nm |GDD(Rs)|<35fs² @500-540nm |GDD(Rp)|<50fs² @510-525nm |GDD(Rs)|<20fs² @1000-1070nm |GDD(Rp)|<40fs² @1010-1055nm
 S2: SCC coating for improved S1 flatness

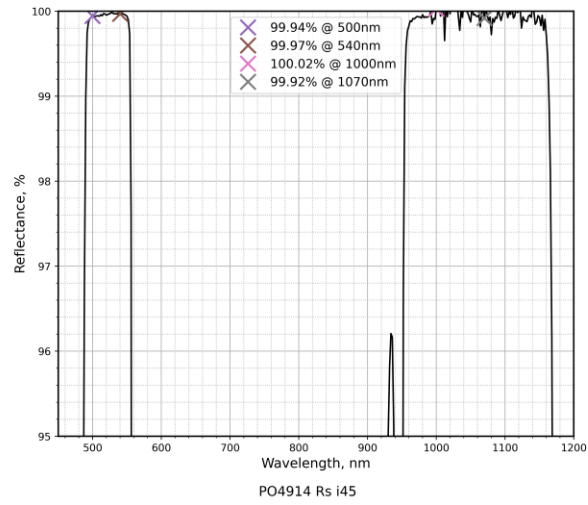


Fig. 1.

SIDE MEASURED: S1 (good component)

COMMENTS: Margin of measurement error: +/-0.25%

S1: (arrow mark) Rs > 99.9% @500-540nm + 1000-1070 nm Rp > 99.8% @507-527nm Rp > 99.9% @1005-1070nm |GDD(Rs)|<35fs² @500-540nm |GDD(Rp)|<50fs² @510-525nm |GDD(Rs)|<20fs² @1000-1070nm |GDD(Rp)|<40fs² @1010-1055nm
 S2: SCC coating for improved S1 flatness

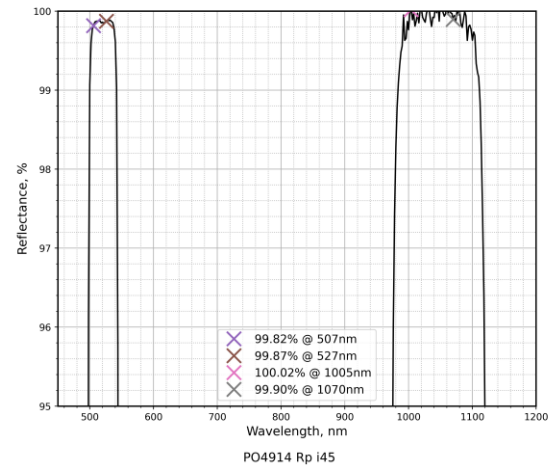


Fig. 2.

SIDE MEASURED: S1 (good component)

COMMENTS: Margin of measurement error: +/-0.25%

Surface flatness, S1: $<\lambda/8@633$ nm over dia. 9mm aperture

Measurement: PAN5382 per 9 mm CA (Sample 1).iom Pass / Fail Criteria Result:

PASS

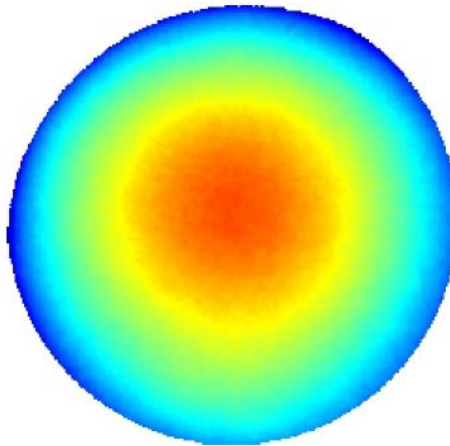
Analysis λ : 633.08 nm

Diameter: 8.863 mm

Fringe

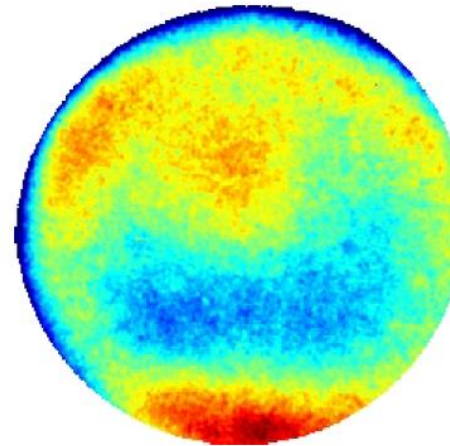


TSD



PV: 0.0965 wv
RMS: 0.0211 wv

IRR



PV: 0.0286 wv
RMS: 0.0033 wv

Calculations

Sagitta: 0.0757 wv

Pass/Fail Criteria [Measured Value]

TSD PV > 0.12 wv[0.0965]

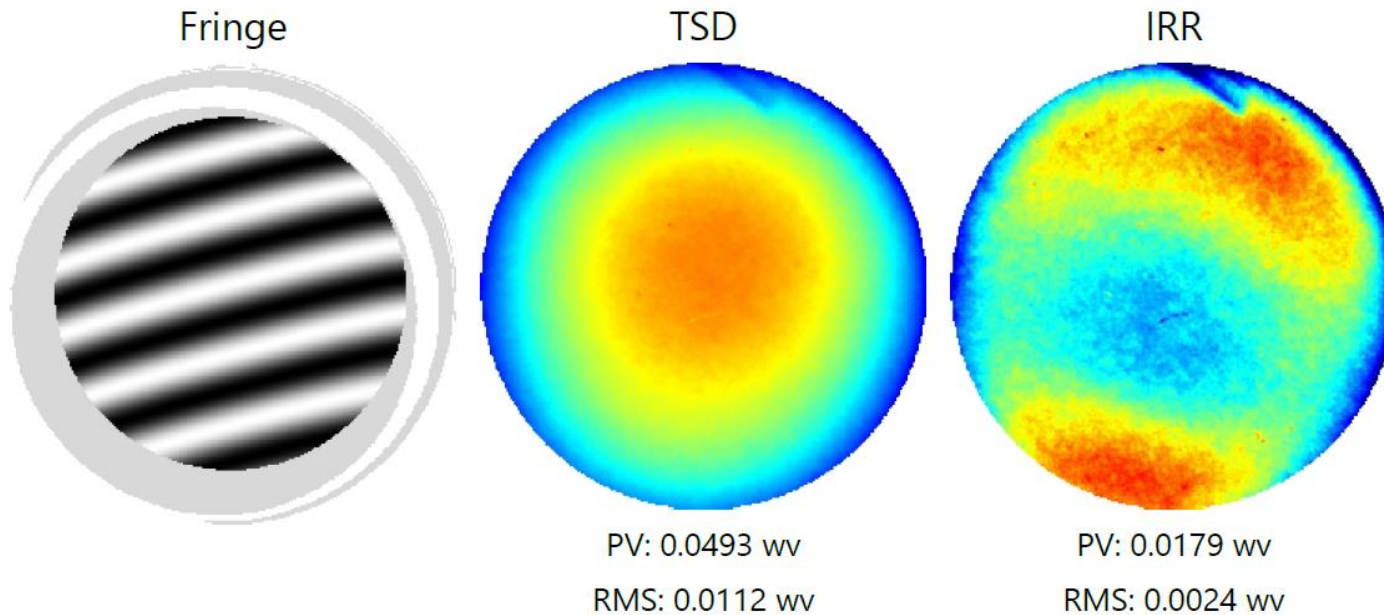
Fig. 3.

Surface flatness, S1: $<\lambda/8@633$ nm over dia. 9mm aperture

Measurement: PAN5382 per 9 mm CA (Sample 2).iom Pass / Fail Criteria Result: **PASS**

Analysis λ : 633.08 nm

Diameter: 8.989 mm



Calculations

Sagitta: 0.038 wv

Pass/Fail Criteria [Measured Value]

TSD PV > 0.12 wv[0.0493]

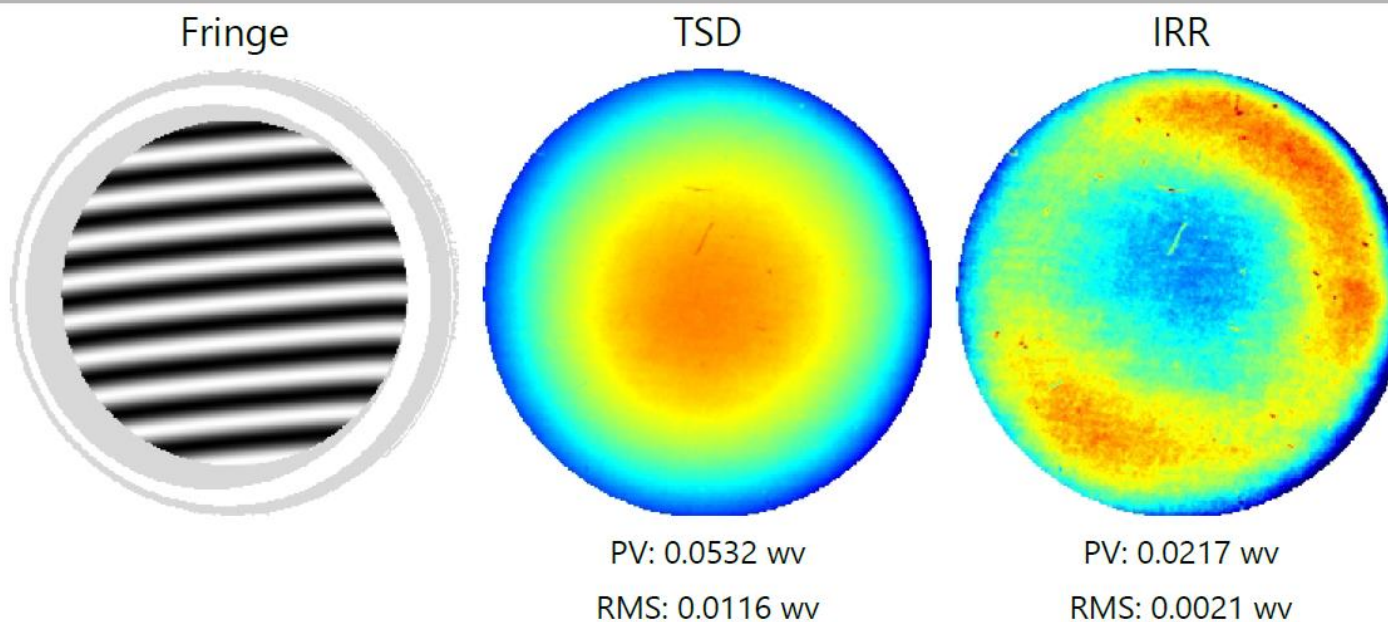
Fig. 4.

Surface flatness, S1: $<\lambda/8@633$ nm over dia. 9mm aperture

Measurement: PAN5382 per 9 mm CA (Sample 3).iom Pass / Fail Criteria Result: **PASS**

Analysis λ : 633.08 nm

Diameter: 8.989 mm



Calculations

Sagitta: 0.0394 wv

Pass/Fail Criteria [Measured Value]

TSD PV > 0.12 wv[0.0532]

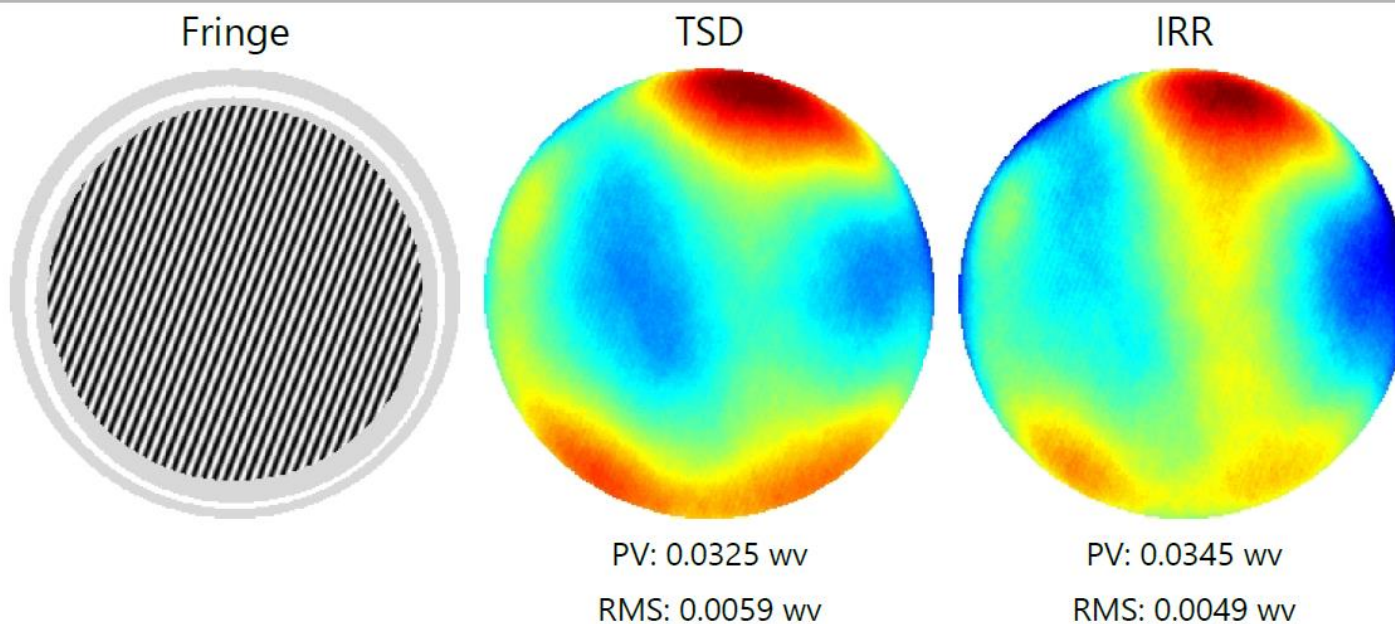
Fig. 5.

Surface flatness, S1: $<\lambda/6@633$ nm over dia. 40mm aperture

Measurement: PAN5383 per 40 mm CA (Sample 1).ior Pass / Fail Criteria Result: **PASS**

Analysis λ : 633.08 nm

Diameter: 39.955 mm



Calculations

Sagitta: 0.0113 wv

Pass/Fail Criteria [Measured Value]

TSD PV > 0.16 wv[0.0325]

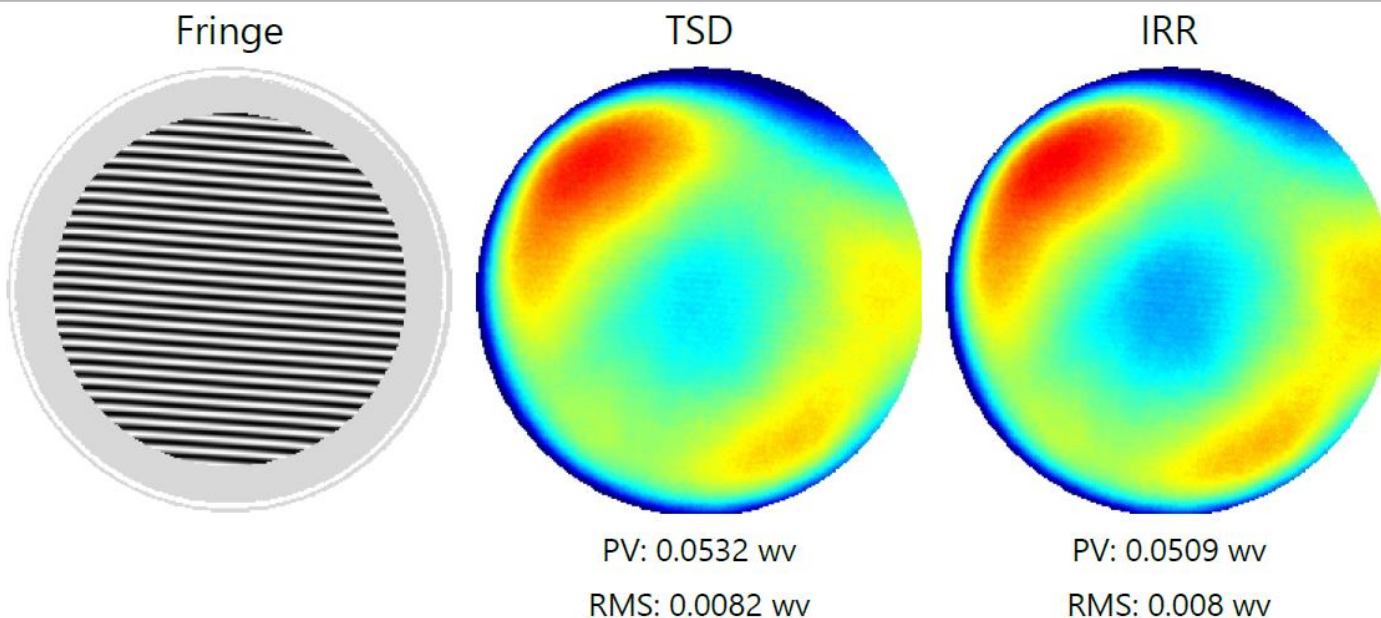
Fig. 6.

Surface flatness, S1: $<\lambda/6@633$ nm over dia. 40mm aperture

Measurement: PAN5383 per 40 mm CA (Sample 2).ior Pass / Fail Criteria Result: **PASS**

Analysis λ : 633.08 nm

Diameter: 39.96 mm



Calculations

Sagitta: 0.0062 wv

Pass/Fail Criteria [Measured Value]

TSD PV > 0.16 wv[0.0532]

Fig. 7.